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United States Patent [19]

Nightingale et al.

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[45] **Date of Patent: ** Apr. 26, 1994**

[54] **ELECTRICAL TEST PROBE**

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[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[**] Term: **14 Years**

[21] Appl. No.: **5,220**

[22] Filed: **Feb. 26, 1993**

[52] **U.S. Cl.** **D10/78**

[58] **Field of Search** .... 324/72.5, 158 P; D10/78

[56] **References Cited**

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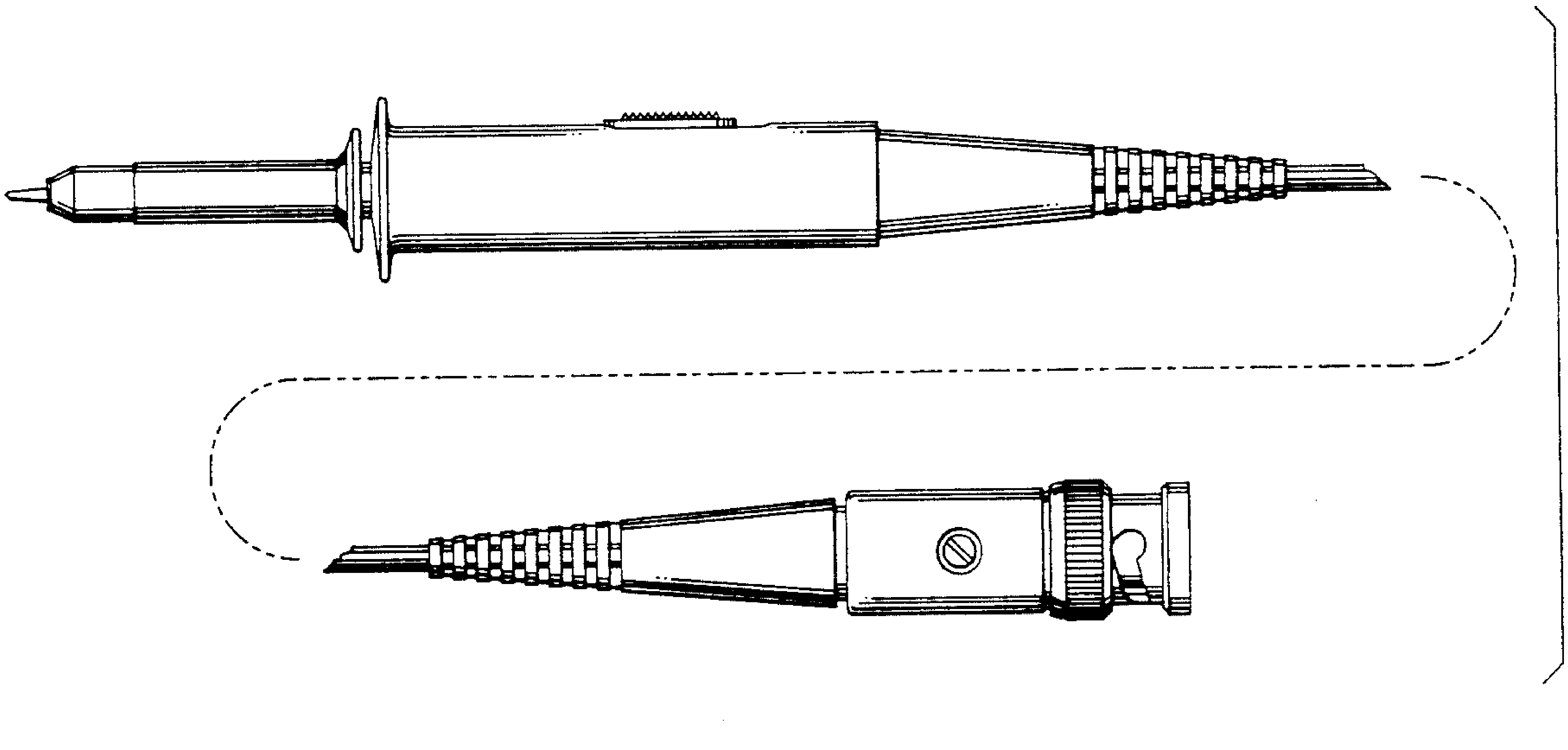
[57] **CLAIM**

The ornamental design for an electrical test probe, as shown and described.

DESCRIPTION

FIG. **1** is a left side elevation view of the electrical test probe showing our new design;
FIG. **2** is a right side elevation view thereof;
FIG. **3** is a top plan view thereof;
FIG. **4** is a bottom plan view thereof;
FIG. **5** is a rear elevation view thereof; and,
FIG. **6** is a front elevation view thereof.
Portions of the cord member have been eliminated for ease of illustration.



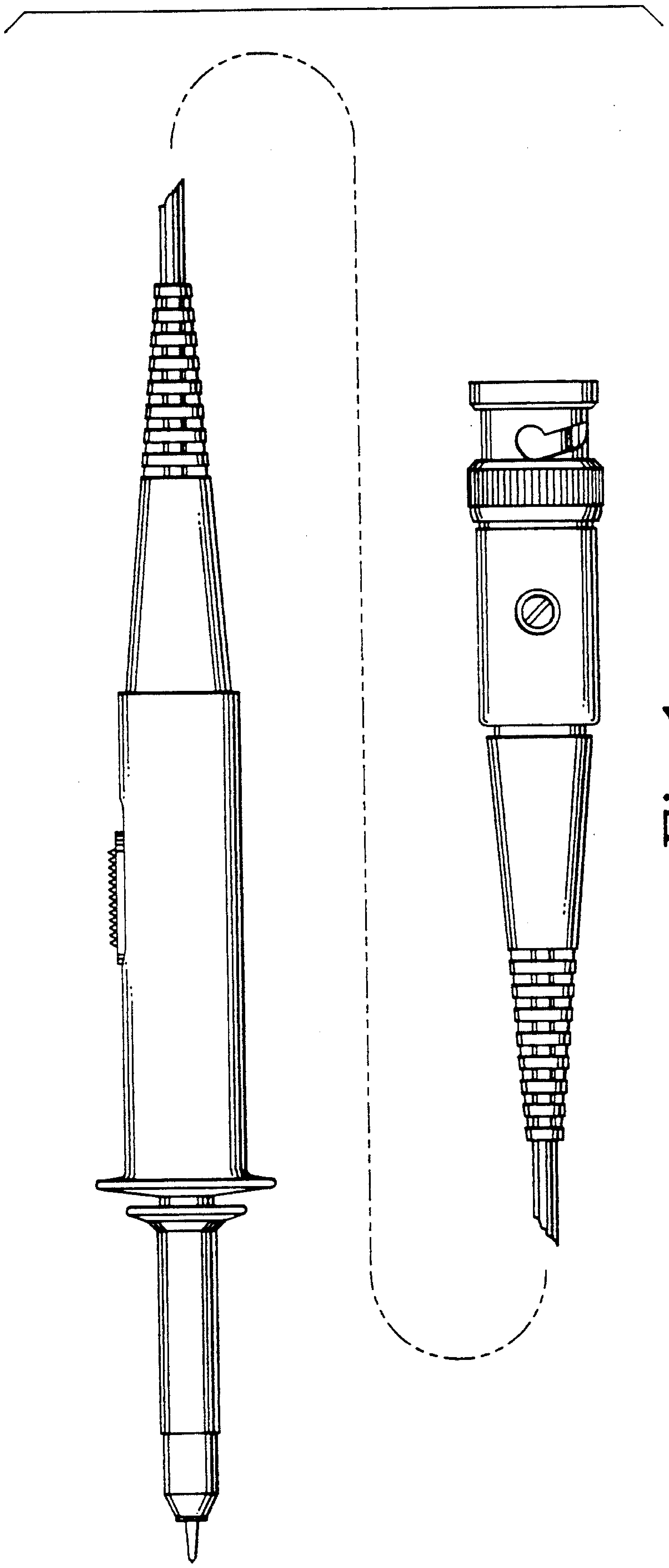


Fig. 1

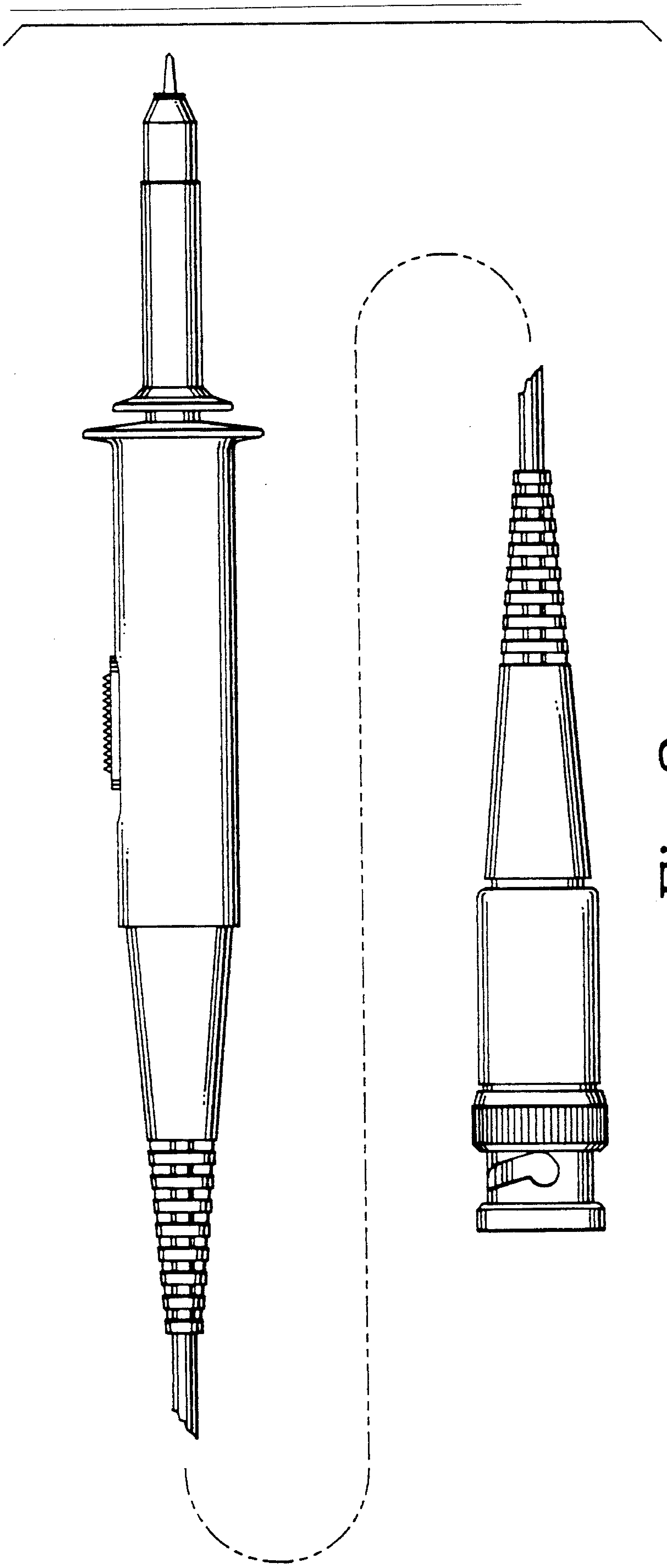


Fig. 2

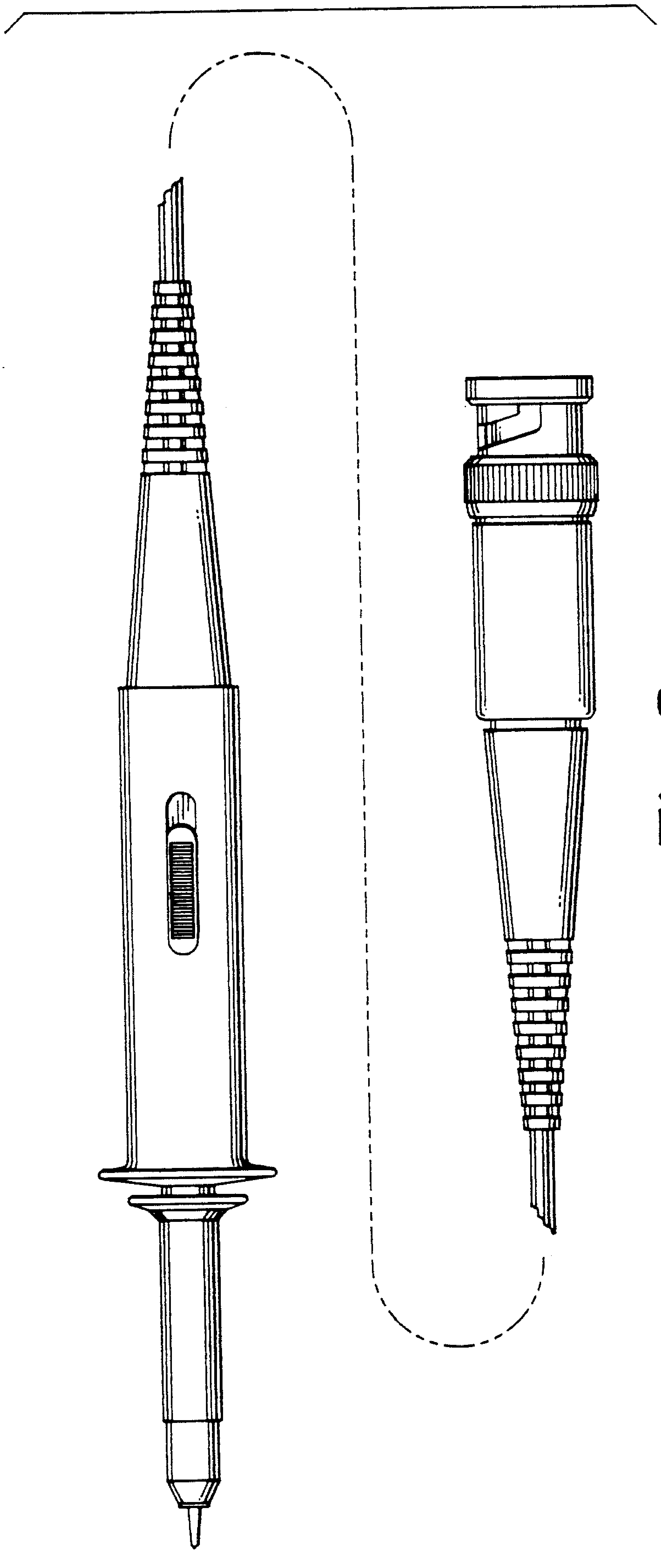


Fig. 3

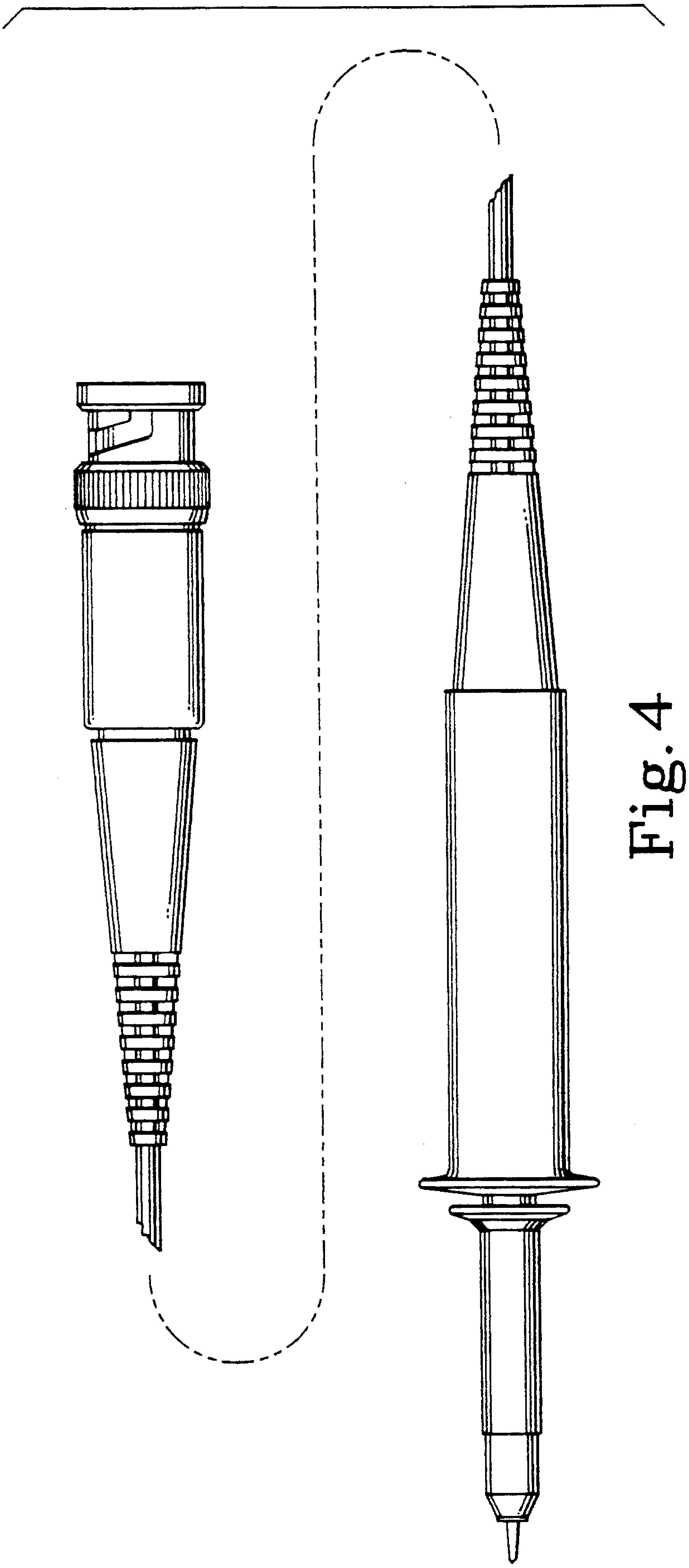


Fig. 4

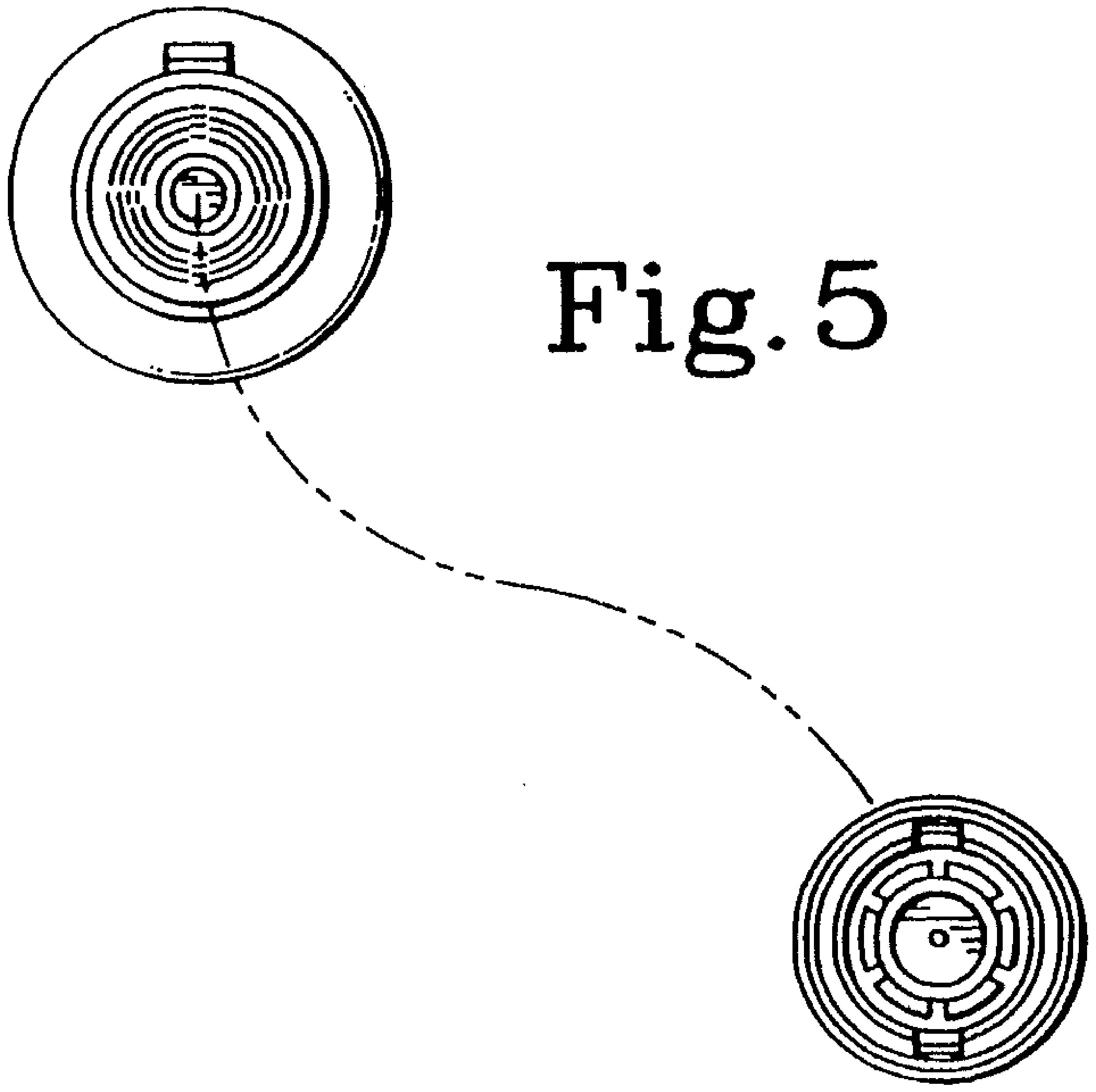


Fig. 5

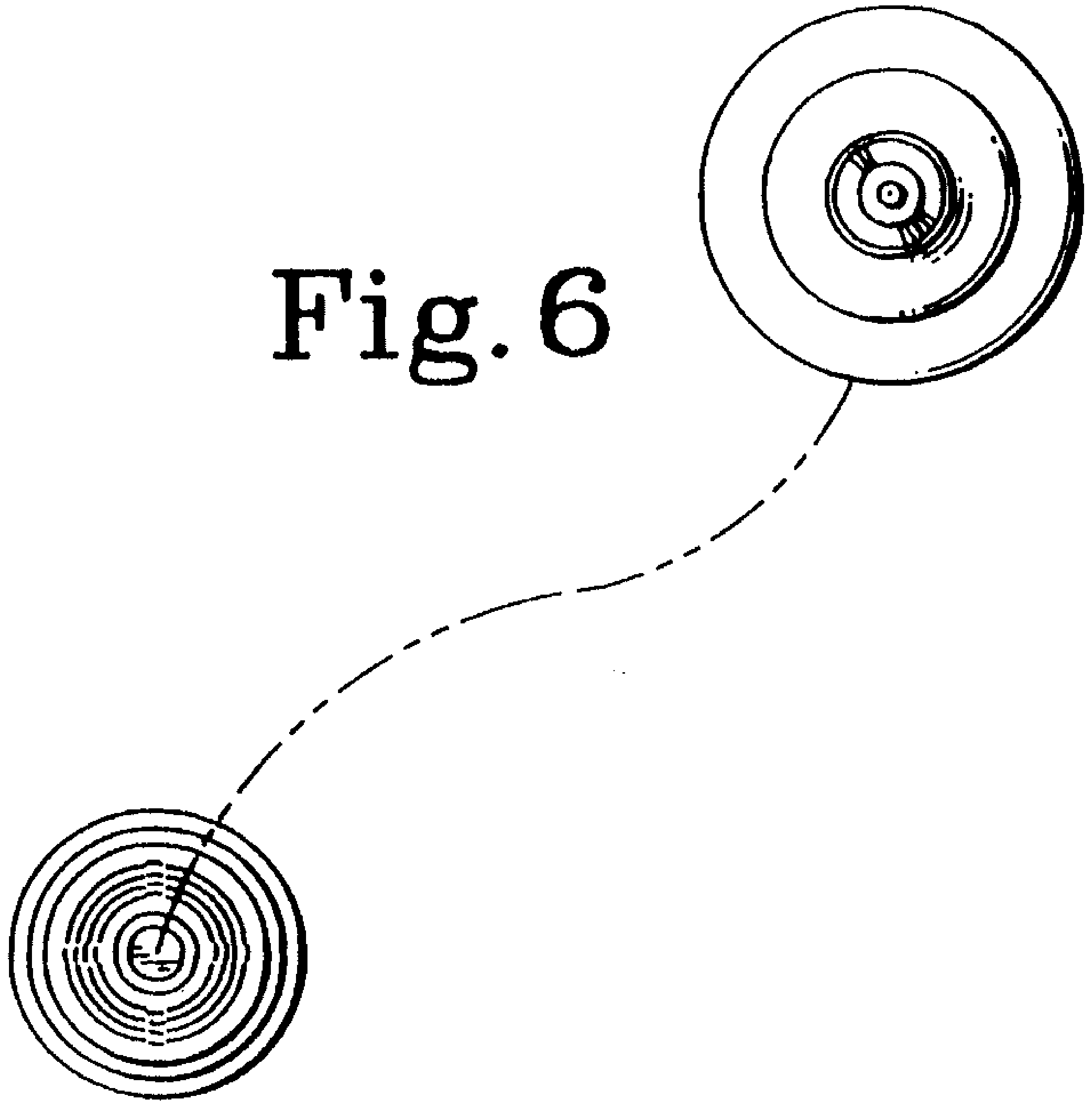


Fig. 6